

**PRODUCTS** 

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## Nanofocus Electron Sources

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### **Products**

### > RHEED

- > AUGER / XPS / EELS / REELS
- > Electron Sources
  - General Purpose Electron
    - Sources
  - Microfocus and Nanofocus Electron
    - > EM-503

Sources

- > EM-506
- > EM-802
- > EF-1005
- > EF-1201
- > EF-1202
- > EF-15005
- Electron FloodSources
- High Energy Small Focus Electron Sources
- High BeamPower Electron
  - Sources
- > Low Energy Electron

# EF-15005

This electron gun column is designed to generate a very small spot in the nm range. It is also available as part of a complete scanning electron imaging package (SEM-package).

## Key features

- Beam size (min.) <85 nm at max energy and</li>
  12 mm working distance
- Energy range 200 eV 15 keV
- Beam current (max.) 1 μA

#### Characteristics

- Working Distance (WD) 10 mm 50 mm
- Optimum WD 12 mm nominal
- Basic beam blanking (optional)
- Beam blanking, external (optional)
- Beam pulsing (optional)
- Computer control (optional)
- Magnetic shielding (optional)
- Beam scanning (optional)
- Microprocessor controlled beam current regulation (optional)
- Remote control



Not all parameters can be reached simultaneously. Above specifications may change without notice. Pictures / diagrams for reference only.

Typical Applications

AES- Depth profiling

**Related Products** 

Filaments

Absorbent current EM (electron Pre-mounted, pre-aligned Sources > Electron cathode units microscope) Sources for Elastically scattered EM (electron Complete service kit RHEED microscope) Diagnostic box > Accessories for **UHV Scanning Electron** Scan amplifier Electron Microscopy (SEM) Faraday cups Sources Scanning Auger Microscopy > Ion Sources Sample current measurement kit (SAM) > X-ray Source Gun control module Auger Electron Spectroscopy > Energy Analyzers & AES and XPS energy (AES) **Imaging Energy** spectrometers (ESA and DESA) **Filters Electron Energy Loss** Secondary Electron Detectors > Charged Particle Spectroscopy (EELS) / Reflection (SED) for imaging **Energy Energy Loss Spectroscopy Detectors** Scanning and imaging package > PEEM & IEEM (REELS) (SEM Package) > UHV-Systems for Sample imaging Surface Analysis EBSD energy filter and detector **Electron Backscattered** > Packages for

Diffraction (EBSD)

X-ray emission analyses

Surface Analysis

> Data Acquisition & Instrument Control

Software

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